

## Supporting Information

### **Ultra-thin lead oxide piezoelectric layers for reduced environmental contamination using a liquid metal-based process**

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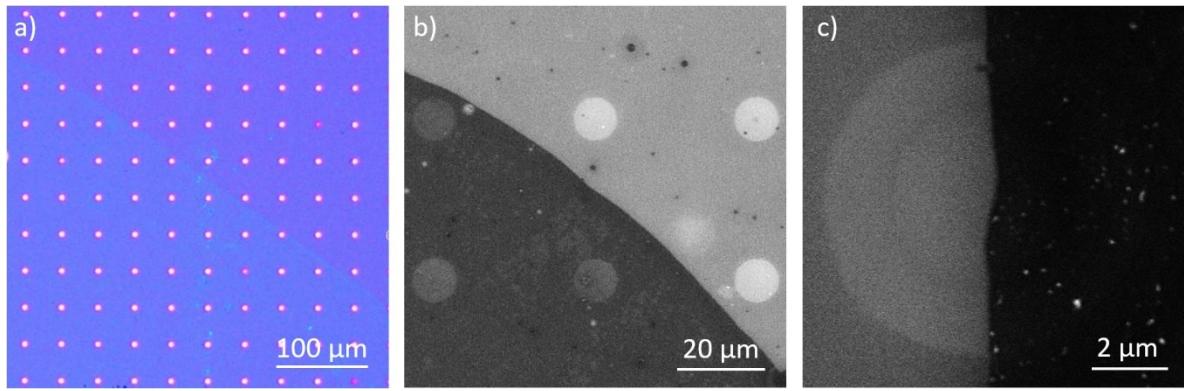
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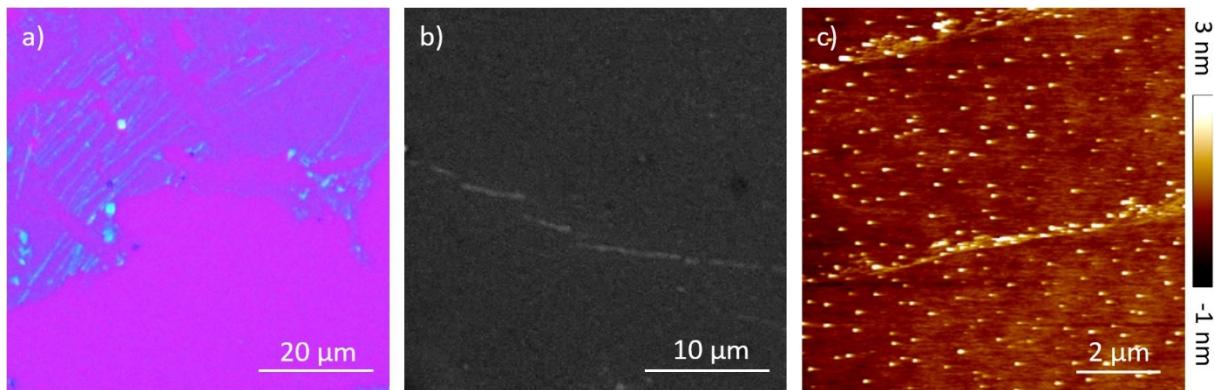
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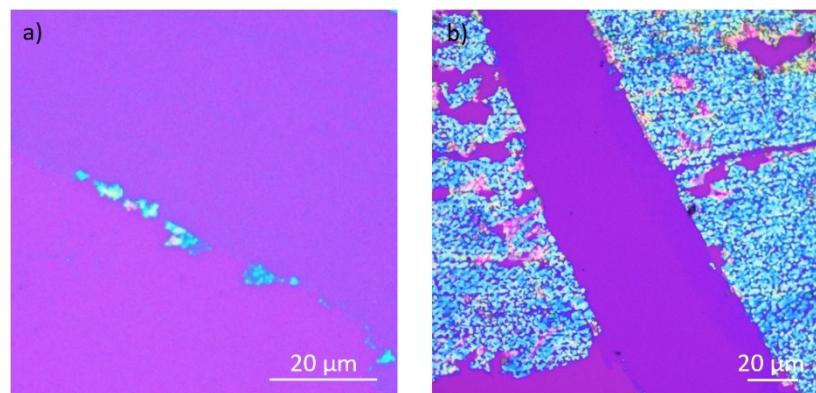
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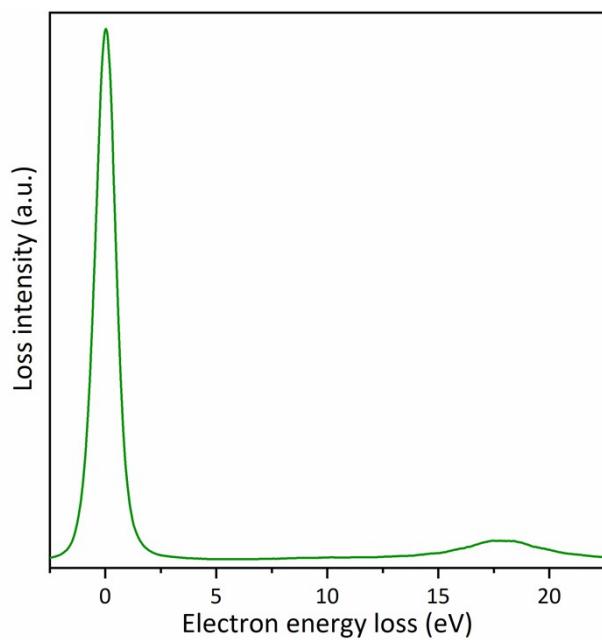
**Fig. S1** (a) Optical and (b,c) SEM images of the 2D PbO on a holey  $\text{SiO}_2/\text{Si}$  substrate.



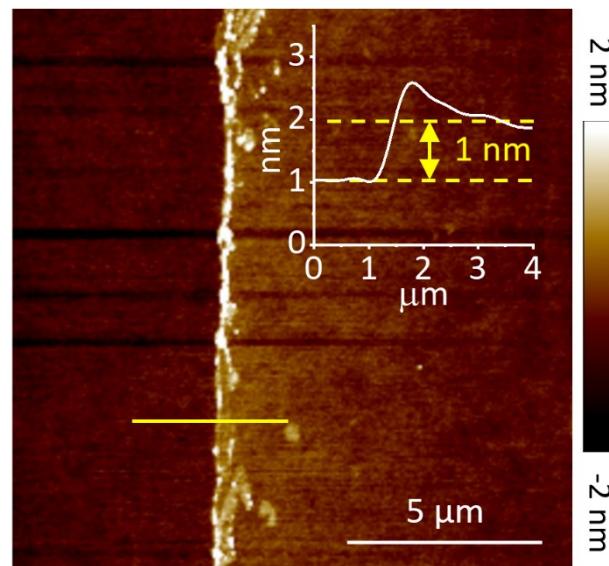
**Fig. S2** (a) Optical, (b) SEM and (c) AFM images of the 2D PbO wrinkles on a  $\text{SiO}_2/\text{Si}$  substrate.



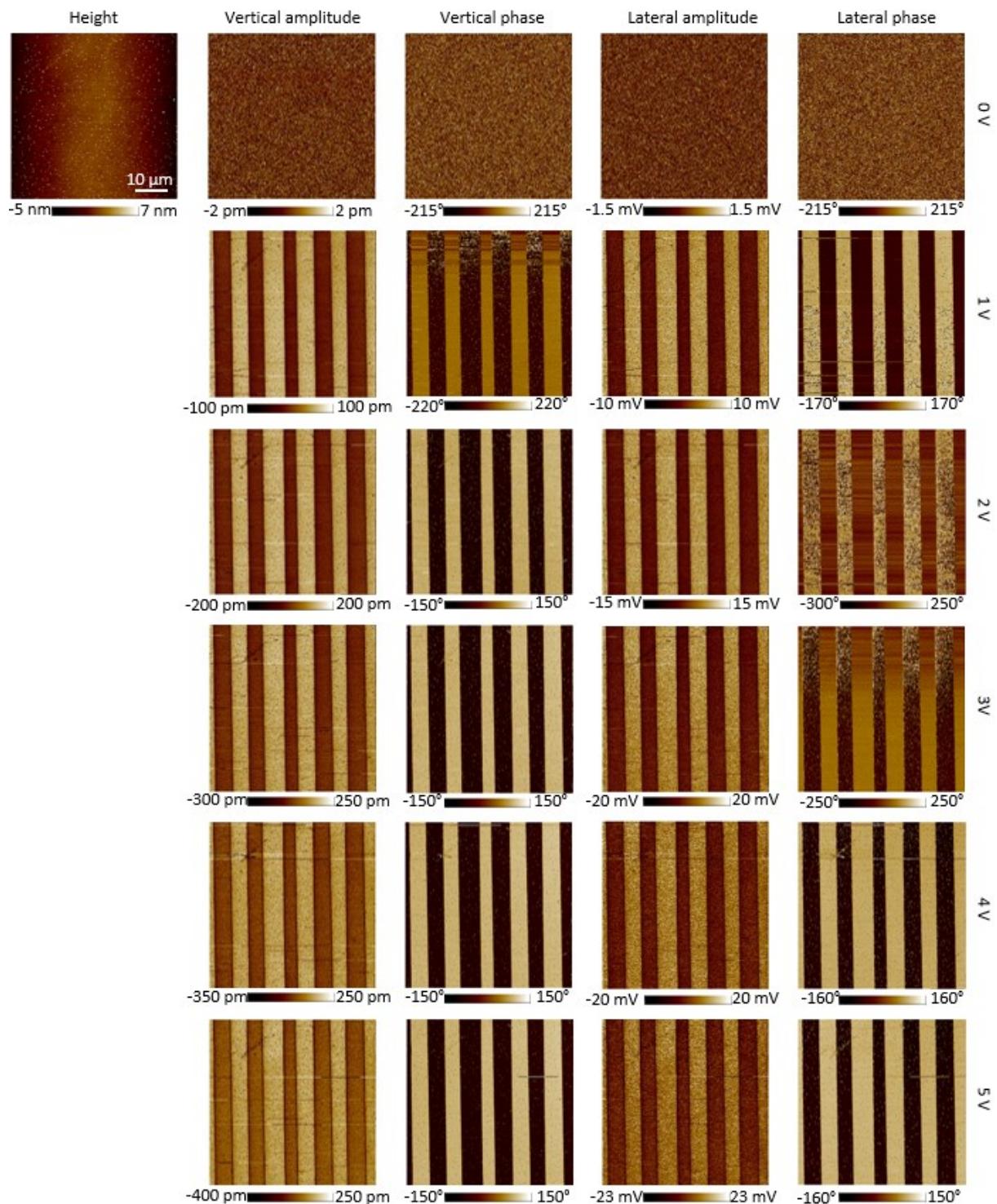
**Fig. S3** Bulk lead oxides on the edges of monolayer PbO after (a) short and (b) long (15 min) oxidation periods.



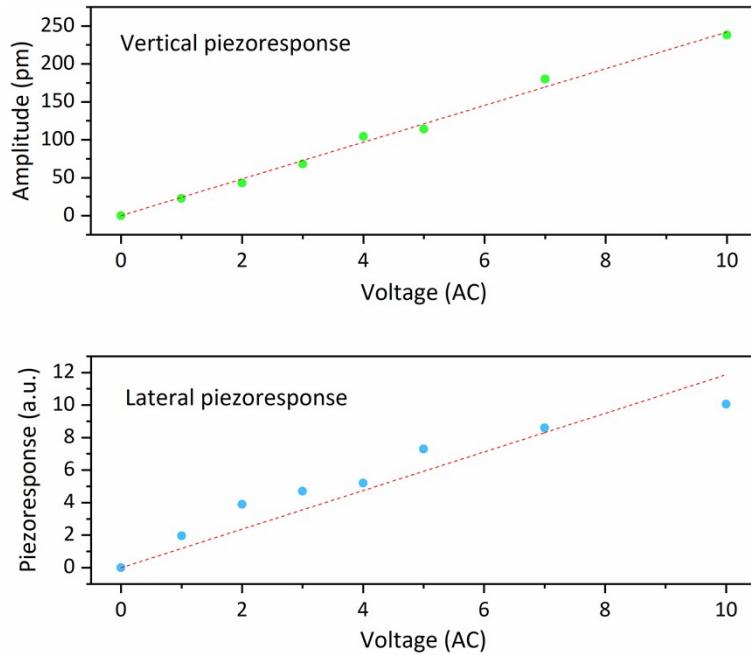
**Fig. S4** The EELS spectrum of 2D PbO nanosheets.



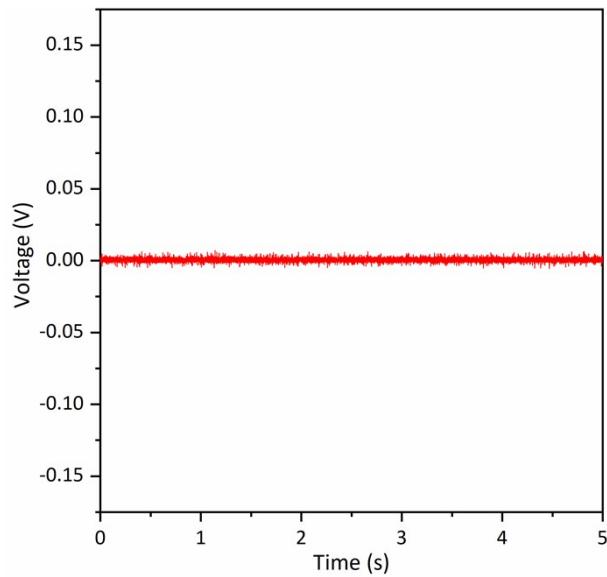
**Fig. S5** The AFM image of the area of 2D PbO used for piezoelectricity measurements.



**Fig. S6** Topography, amplitude, and phase variation of PPLN as the function of magnitudes of AC driving voltages.



**Fig. S7** Extended vertical and lateral piezoresponse amplitudes of the PbO monolayer as the function of AC driving voltage.



**Fig. S8** Voltage output from the bare (no PbO layer) mica device after applying mechanical stimuli.

**Table S1.** Computed piezoelectric stress tensor (in C m<sup>-2</sup>) and relevant elastic tensors (in GPa) components for a metastable  $\beta$ -PbO structure.

e <sub>31</sub>	e <sub>32</sub>	e <sub>33</sub>	C <sub>11</sub>	C <sub>12</sub>	C <sub>13</sub>	C <sub>22</sub>	C <sub>23</sub>	C <sub>33</sub>
0.069	0.069	-0.173	4.4	0.8	0.8	11.8	3.0	7.4

**Table S2.** Vertical and lateral piezoresponses of some 2D materials.

Material	Vertical piezoresponse (pm/V)	Lateral piezoresponse (pm/V)	Ref.	Material	Vertical piezoresponse (pm/V)	Lateral piezoresponse (pm/V)	Ref.
C <sub>3</sub> N <sub>4</sub>	1		1	GaSe	2.30		2
MoSSe		0.020	3	GaS	2.06		2
MoSTe		0.028	3	InSe	1.46		2
MoSeTe		0.030	3	Graphene oxide		0.24	4
WSSe		0.011	3	GaInTe <sub>2</sub>		0.32	5
WSTe		0.007	3	GaInSe <sub>2</sub>		0.46	5
WSeTe		0.008	3	GaInS <sub>2</sub>		0.38	5
MoS <sub>2</sub>	1.35		6	Ga <sub>2</sub> SeTe		0.21	5
GaPO <sub>4</sub>	8.5		7	Ga <sub>2</sub> STe		0.25	5
$\alpha$ -In <sub>2</sub> Se <sub>3</sub>	0.34		8	Ga <sub>2</sub> SSe		0.07	5
CdS	32.8		9	In <sub>2</sub> SeTe		0.13	5
ZnO	23.7		10	In <sub>2</sub> STe		0.25	5
ZnO	21.5		11	In <sub>2</sub> SSe		0.18	5
Graphene on SiO <sub>2</sub>	14		12	MoS <sub>2</sub>	1.03		13
Graphene doped with K		0.23	14	MoSSe	0.1		15
Graphene doped with Li		0.15	14	BaTiO <sub>3</sub>	8		16
Graphene doped with H		0.11	14	PVDF	-36		17
Graphene doped with F		0.0018	14	PZT	7-15		18
Graphene doped with F, Li		0.30	14	PbO	29.6	3.9	This work
Graphene doped with H, F		0.034	14				

## References

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